## Notice of References Cited Application/Control S: Applicant(s)/Patent Under Reexamination CHEN, SHIUH-YUAN Examiner Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,424,940	07-2002	Agassy et al.	704/219
*	В	US-6,075,906	06-2000	Fenwick et al.	382/298
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	j	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	P					
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	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	x						

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